



TEST REPORT

Applicant : SHANGHAI MOUNTAIN VIEW SILICON CO., LTD
PRODUCT NAME : MV_BP10xx PCB Antenna
MODEL NAME : MV_BP10
TRADE NAME : MVSILICON
BRAND NAME : MVSILICON
STANDARD(S) : ANSI/IEEE Std 149-2008
RECEIPT DATE : 2019-08-30
TEST DATE : 2019-09-02
ISSUE DATE : 2019-10-15



Edited by:

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Approved by:

Andy Yeh(Technical Director)

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Change History		
Version	Date	Reason for change
1.0	2019-10-15	First edition



1. Technical Information

Note: Provide by manufacturer.

1.1. Manufacturer and Factory Information

Applicant:	SHANGHAI MOUNTAIN VIEW SILICON CO., LTD
Applicant Address:	Suite 4C, Building 3, 1238 Zhangjiang Road, Pudong New District, Shanghai, China
Manufacturer:	SHANGHAI MOUNTAIN VIEW SILICON CO., LTD
Manufacturer Address:	Suite 4C, Building 3, 1238 Zhangjiang Road, Pudong New District, Shanghai, China

1.2. Equipment Under Test (EUT) Description

Wireless Type	N/A
Frequency	N/A



2. Test Results

2.1. Applied Reference Documents

Leading reference documents for testing:

No.	Identity	Document Title
1	ANSI/IEEE Std 149-2008	IEEE Standard Test Procedures for Antennas

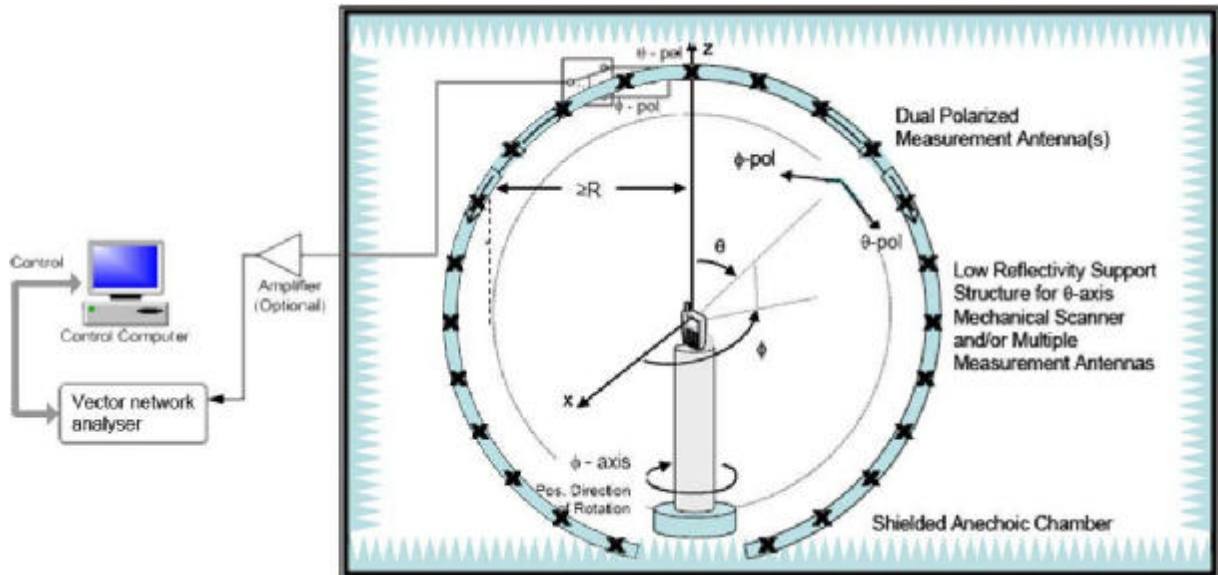
2.2. Test Conditions

Test Environment Conditions:

Relative Humidity:	25 ... 75 %
Temperature:	+10 °C to +30 °C

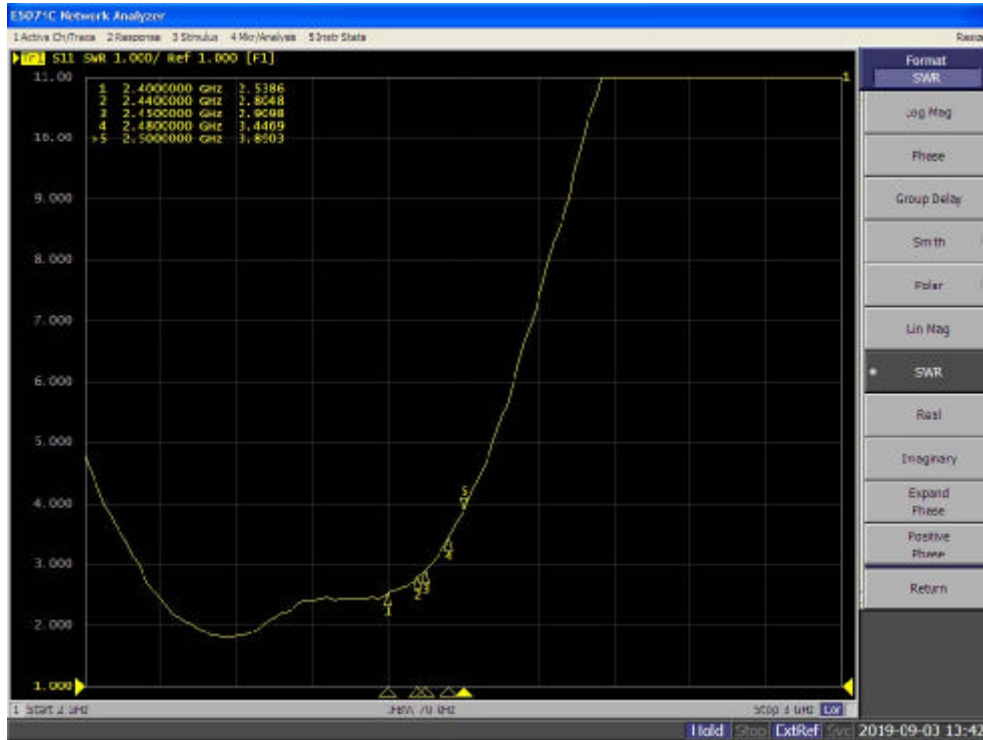
Annex A Photographs

1. Test Setup

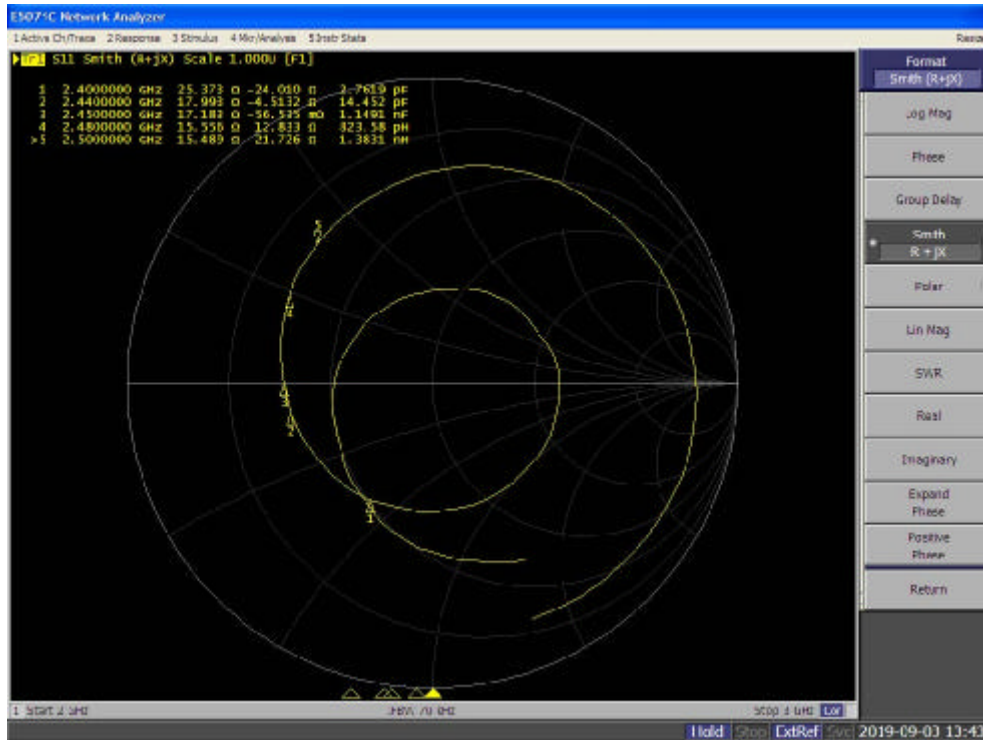




4. VSWR

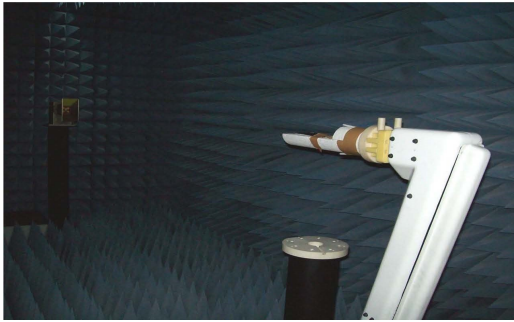
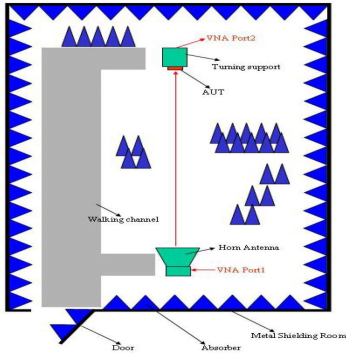


5. Input Impedance

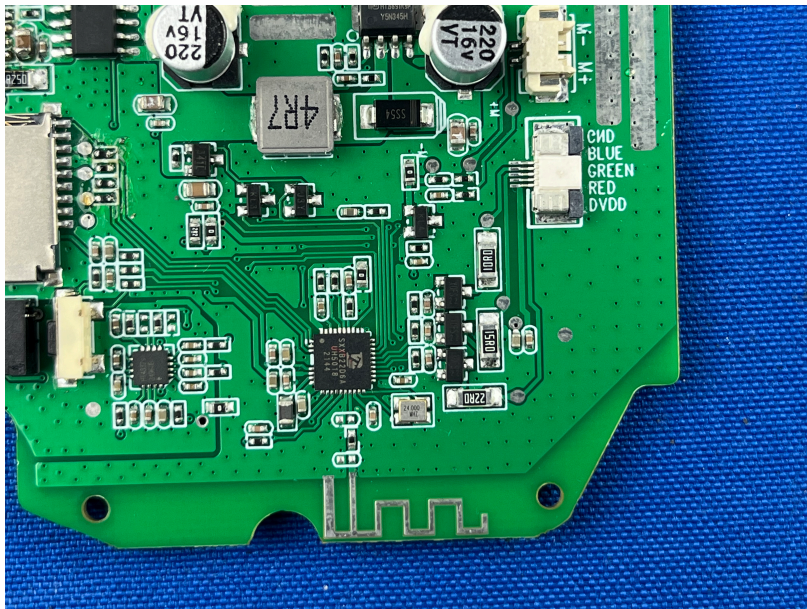


Annex C Photographs

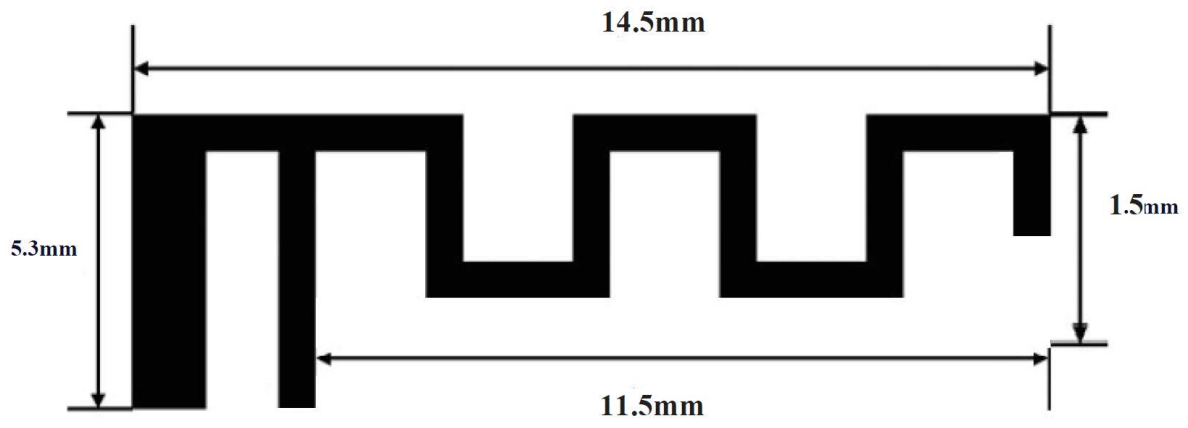
1. Test environment



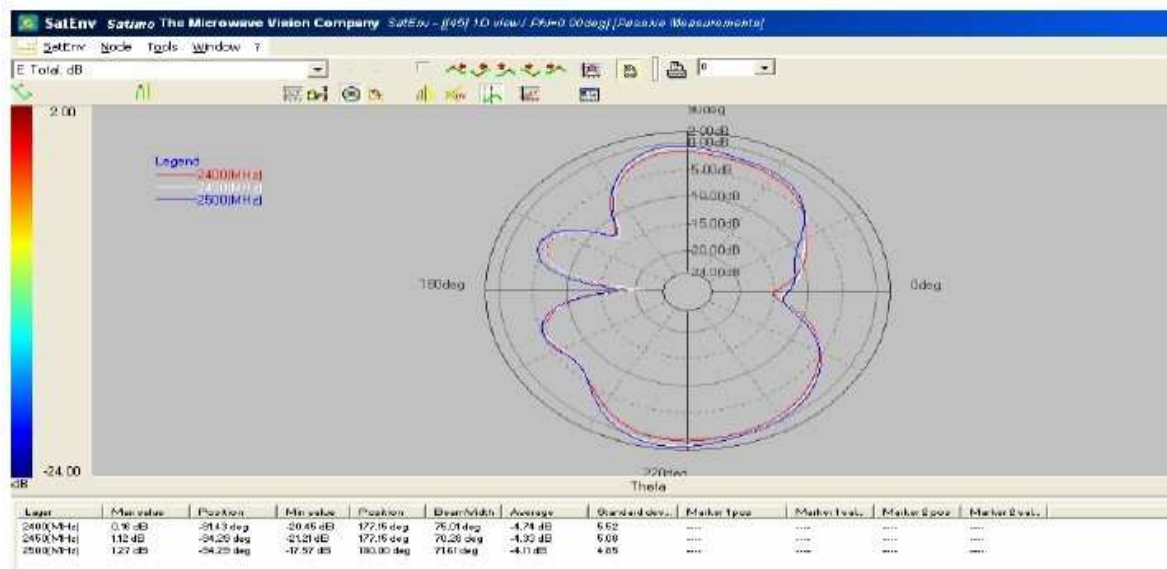
2. EUT



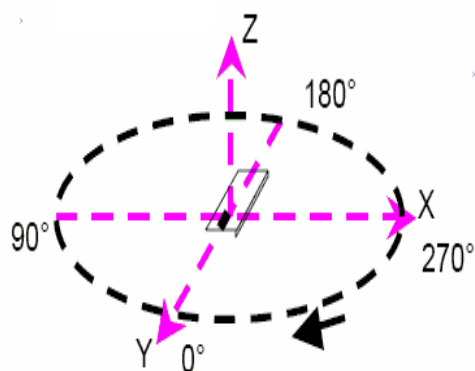
Antenna Photo & Length (mm)



E1 pattern:



Fre (MHz)	Max gain (dB)	Degree
2400	0.16	-91.43
2450	1.12	-94.29
2500	1.27	-94.29





Annex D General Information

1.1 Identification of the Responsible Testing Laboratory

Laboratory Name:	Shenzhen Morlab Communications Technology Co., Ltd. Morlab Laboratory
Laboratory Address:	FL1-3, Building A, FeiYang Science Park, No.8 LongChang Road, Block67, BaoAn District, ShenZhen , GuangDong Province, P. R. China
Telephone:	+86 755 36698555
Facsimile:	+86 755 36698525

1.2 Identification of the Responsible Testing Location

Name:	Shenzhen Morlab Communications Technology Co., Ltd. Morlab Laboratory
Address:	FL1-3, Building A, FeiYang Science Park, No.8 LongChang Road, Block67, BaoAn District, ShenZhen , GuangDong Province, P. R. China

1.3 Test Equipments Utilized

1.3.1 List of Test Equipment

No.	Type	Specification
1	E5071C Vector Network Analyzer	Manufacturer: Agilent
2	4*4*4 Full Anechoic Chamber	Manufacturer: Satimo
3	SG24 Multi-probe Antenna Measurement System	Manufacturer: Satimo

————— END OF REPORT —————